## Features

- Functionally and Pin Compatible with the Atmel Commercial and Military AT40K Series
- Ultra High Performance
  - System Speeds 60 MHz
  - Array Multipliers > 32 MHz
  - 18 ns Flexible SRAM
  - Internal Tri-state Capability in Each Cell
- FreeRAM<sup>™</sup>
  - Flexible, Single/Dual Port, Sync/Async 18 ns SRAM
  - 18432 Bits of Distributed SRAM Independent of Logic Cells for AT40KEL040
- 384 PCI Compliant I/Os
  - Programmable Output Drive
  - Fast, Flexible Array Access Facilitates Pin Locking
- 8 Global Clocks
  - Fast, Low Skew Clock Distribution
  - Programmable Rising/Falling Edge Transitions
  - Distributed Clock Shutdown Capability for Low Power Management
  - Global Reset/Asynchronous Reset Options
  - 4 Additional Dedicated PCI Clocks
- Cache Logic<sup>®</sup> Dynamic Full/Partial Reconfigurability In-System
  - Unlimited Reprogrammability via Serial or Parallel Modes
  - Enables Adaptive Designs
  - Enables Fast Vector Multiplier Updates
  - Quick-Change<sup>™</sup> Tools for Fast, Easy Design Changes
- Package Options
  - MQFPF160
    - MQFPF256
- Industry-standard Design Tools
  - Seamless Integration (Libraries, Interface, Full Back-annotation) with Exemplar<sup>™</sup>, Mentor<sup>®</sup>, Synplicity<sup>®</sup>
    - Timing Driven Placement & Routing
    - Automatic/Interactive Multi-chip Partitioning
    - Fast, Efficient Synthesis
    - Over 75 Automatic Component Generators Create 1000s of Reusable, Fully Deterministic Logic and RAM Functions
- Intellectual Property Cores
- Fir Filters, UARTs, PCI, FFT and Other System Level Functions
- Easy Migration to Atmel Gate Arrays for High Volume Production
- Supply Voltage 3.3V
- 200 Krads (TM 1019.5)
- Latch-up Threshold Higher than 70 MeV.cm<sup>2</sup>/mg
- Built-in SEU Hardening
- Quality Grades
  - QML -Q and -V with SMD 5962-03250
  - ESCC B with 9301/051
- Design Tools

 Design Kit (AT40KEL-DK) Including: Mother Board
Daughter Board for MQFPF160
AT17 Series Configuration Memory ISP Download Cable
System Designer CD-ROM (Including IDS Tool)

 Additional Daughter Board Variant: ATDH40D256M: for MQFPF256



Rad Hard Reprogrammable FPGAs with FreeRAM<sup>™</sup>





#### Table 1. AT40KEL040

Device	AT40KEL040
Usable Gates	40K - 50K
Rows x Columns	48 x 48
Cells	2,304
Registers	3,048 <sup>(1)</sup>
RAM Bits	2304
I/O (max)	384

Note: 1. Packages with FCK will have 8 less clocks.

## Description

The AT40KEL040 is a fully PCI-compliant, SRAM-based FPGA with distributed 18 ns programmable synchronous/asynchronous, dual port/single port SRAM, 8 global clocks, Cache Logic ability (partially or fully reconfigurable without loss of data), automatic component generators, and 50,000 usable gates. I/O counts range from 128 to 384 in Aerospace standard packages and support 3.3V.

The AT40KEL040 is designed to quickly implement high performance, large gate count designs through the use of synthesis and schematic-based tools used on a PC and Sun<sup>™</sup> platform. Atmel's design tools provide seamless integration with industry standard tools such as Synplicity, Modelsim, Exemplar and Viewlogic. See the IDS datasheet for other supported tools.

The AT40KEL040 can be used as a co-processor for high-speed (DSP/processorbased) designs by implementing a variety of compute-intensive, arithmetic functions. These include adaptive finite impulse response (FIR) filters, Fast Fourier Transforms (FFT), convolvers, interpolators and discrete-cosine transforms (DCT) that are required for video compression and decompression, encryption, convolution and other multimedia applications.

Fast, Flexible and<br/>Efficient SRAMThe AT40KEL040 FPGA offers a patented distributed 11 - 13 ns SRAM capability where<br/>the RAM can be used without losing logic resources. Multiple independent, synchronous<br/>or asynchronous, dual port or single port RAM functions (FIFO, scratch pad, etc.) can be<br/>created using Atmel's macro generator tool.

**Fast, Efficient Array and Vector Multipliers** The AT40KEL040's patented 8-sided core cell with direct horizontal, vertical and diagonal cell-to-cell connections implements ultra fast array multipliers without using any busing resources. The AT40KEL040's Cache Logic capability enables a large number of design coefficients and variables to be implemented in a very small amount of silicon, enabling vast improvement in system speed at much lower cost than conventional FPGAs.

**Cache Logic Design** The AT40KEL040 is capable of implementing Cache Logic (Dynamic full/partial logic reconfiguration, without loss of data, on-the-fly) for building adaptive logic and systems. As new logic functions are required, they can be loaded into the logic cache without losing the data already there or disrupting the operation of the rest of the chip; replacing or complementing the active logic. The AT40KEL040 can act as a reconfigurable co-processor.

#### Automatic Component Generators The AT40KEL040 FPGA family is capable of implementing user-defined, automatically generated, macros in multiple designs; speed and functionality are unaffected by the macro orientation or density of the target device. This enables the fastest, most predictable and efficient FPGA design approach and minimizes design risk by reusing already

proven functions. The Automatic Component Generators work seamlessly with industrystandard schematic and synthesis tools to create the fastest, most efficient designs available.

The patented AT40KEL040 series architecture employs a symmetrical grid of small yet powerful cells connected to a flexible busing network. Independently controlled clocks and resets govern every column of cells. The array is surrounded by programmable I/O. Devices offer 50,000 usable gates, and have 3,056 registers. AT40K series FPGAs utilize a reliable 0.35µ single-poly, 4-metal CMOS process and are 100% factory-tested. Atmel's PC- and workstation-based integrated development system (IDS) is used to cre-

ate AT40KEL040 series designs. Multiple design entry methods are supported.

The Atmel architecture was developed to provide the highest levels of performance, functional density and design flexibility in an FPGA. The cells in the Atmel array are small, efficient and can implement any pair of Boolean functions of (the same) three inputs or any single Boolean function of four inputs. The cell's small size leads to arrays with large numbers of cells, greatly multiplying the functionality in each cell. A simple, high-speed busing network provides fast, efficient communication over medium and long distances.

### AT40KEL040 Configurator

Statistics extracted from configuration bitstreams show that the maximum needed size is 1Mbit.

In order to keep the maximum number of pins assigned to signals, it is recommended to use a serial configuration interface.

This is the reason why Atmel proposes a 1Mbit serial EEPROM for configuring the AT40KEL040, the AT17LV010-10DP which is also a 3.3V bias chip. It is packaged into a 28-pin DIL Flat Pack 400mils wide.

This memory has been tested for total dose under bias and unbiased conditions, exhibiting far better results when unbiased; this is the reason why it is recommended to switch off the memory when it is not in the configuration mode.

In addition, heavy ions tests have shown that the data stored in the memory cells are not corrupted eventhough errors may be detected while downloading the bitstream; this is the result of the data serialization from the parallel memory plan; therefore, it is recommended to use the FPGA CRC while configuring it, and to resume the configuration when an error is detected.





## The Symmetrical Array

At the heart of the Atmel architecture is a symmetrical array of identical cells (Figure 1). The array is continuous from one edge to the other, except for bus repeaters spaced every four cells (Figure 2 on page 5). At the intersection of each repeater row and column is a 32 x 4 RAM block accessible by adjacent buses. The RAM can be configured as either a single-ported or dual-ported RAM<sup>(1)</sup>, with either synchronous or asynchronous operation.

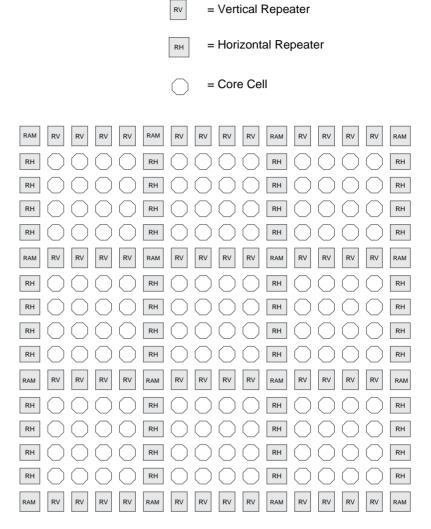
1. The right-most column can only be used as single-port RAM. Note:

Figure 1. Symmetrical Array Surrounded by I/O

$\infty = I/O Pad$ = Repeater Row $\Box$ = Free	RAM
---	-----

 $\circ$  = AT40K Cell = Repeater Column

Note: AT40K has registered I/Os. Group enable every sector for tri-states on obuf's.





- Note:
  - Repeaters regenerate signals and can connect any bus to any other bus (all pathways are legal) on the same plane. Each repeater has connections to two adjacent local-bus segments and two express-bus segments. This is done automatically using the integrated development system (IDS) tool.





## **The Busing Network**

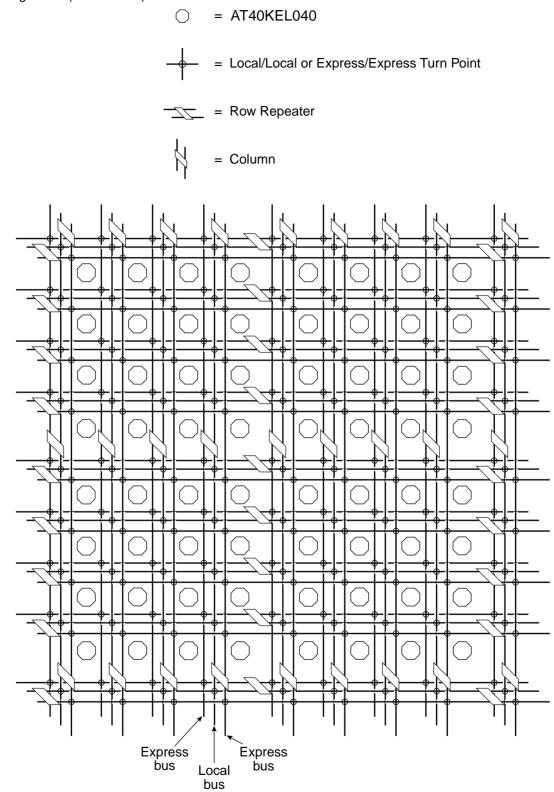
Figure 3 on page 7 depicts one of five identical busing planes. Each plane has three bus resources: a local-bus resource (the middle bus) and two express-bus (both sides) resources. Bus resources are connected via repeaters. Each repeater has connections to two adjacent local-bus segments and two express-bus segments. Each local-bus segment spans four cells and connects to consecutive repeaters. Each express-bus segment spans eight cells and "leapfrogs" or bypasses a repeater. Repeaters regenerate signals and can connect any bus to any other bus (all pathways are legal) on the same plane. Although not shown, a local bus can bypass a repeater via a programmable pass gate allowing long on-chip tri-state buses to be created. Local/Local turns are implemented through pass gates in the cell-bus interface (see following page). Express/Express turns are implemented through separate pass gates distributed throughout the array.

Some of the bus resource on the AT40KEL040 is used as a dual-function resource. Table 2 shows which buses are used in a dual-function mode and which bus plane is used. The AT40KEL040 software tools are designed to accommodate dual-function buses in an efficient manner.

Table 2. Dual-function Buses

Function	Туре	Plane(s)	Direction	Comments
Cell Output Enable	Local	5	Horizontal and Vertical	
RAM Output Enable	Express	2	Vertical	Bus full length at array edge Bus in first column to left of RAM block
RAM Write Enable	Express	1	Vertical	Bus full length at array edge Bus in first column to left of RAM block
RAM Address	Express	1 - 5	Vertical	Buses full length at array edge Buses in second column to left of RAM block
RAM Data In	Local	1	Horizontal	
RAM Data Out	Local	2	Horizontal	
Clocking	Express	4	Vertical	Bus half length at array edge
Set/Reset	Express	5	Vertical	Bus half length at array edge





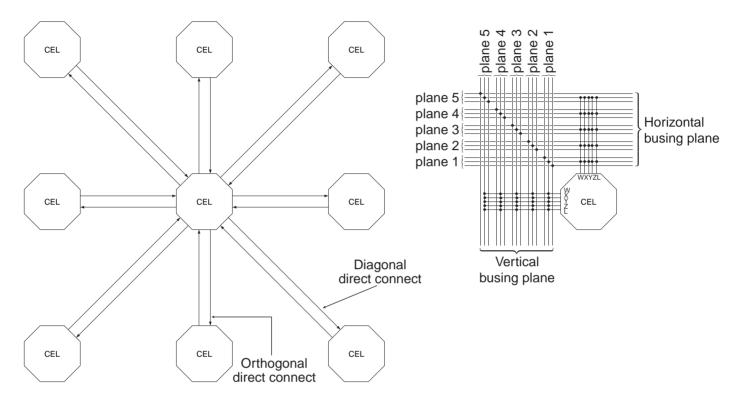


# <u>AMEL</u>

## **Cell Connections**

Figure 4(a) depicts direct connections between a cell and its eight nearest neighbors. Figure 4(b) shows the connections between a cell and five horizontal local buses (1 per busing plane) and five vertical local buses (1 per busing plane).

#### Figure 4. Cell Connections



(a) Cell-to-cell Connections

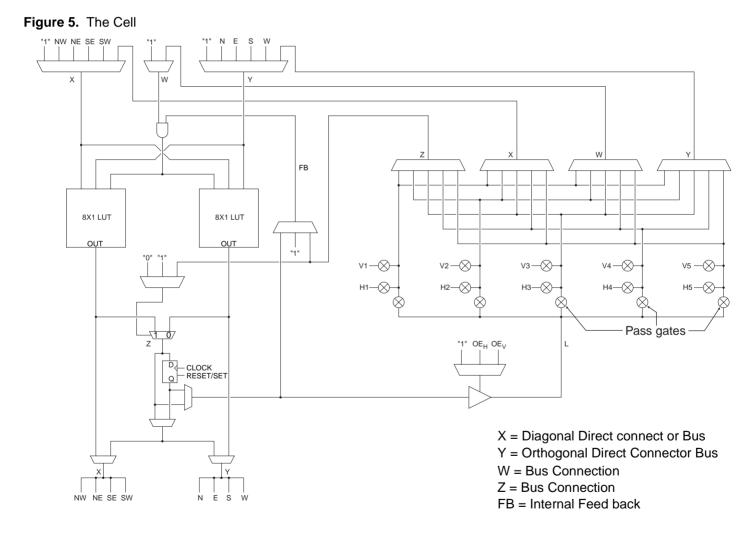
(b) Cell-to-bus Connections

8

## The Cell

Figure 5 depicts the AT40KEL040 cell. Configuration bits for separate muxes and pass gates are independent. All permutations of programmable muxes and pass gates are legal.  $V_n (V_1 - V_5)$  is connected to the vertical local bus in plane n.  $H_n (H_1 - H_5)$  is connected to the horizontal local bus in plane n. A local/local turn in plane n is achieved by turning on the two pass gates connected to  $V_n$  and  $H_n$ . Pass gates are opened to let signals into the cell from a local bus or to drive a signal out onto a local bus. Signals coming into the logic cell on one local bus plane can be switched onto another plane by opening two of the pass gates. This allows bus signals to switch planes to achieve greater routability. Up to five simultaneous local/local turns are possible.

The AT40KEL040 FPGA core cell is a highly configurable logic block based around two 3-input LUTs (8 x 1 ROM), which can be combined to produce one 4-input LUT. This means that any core cell can implement two functions of 3 inputs or one function of 4 inputs. There is a Set/Reset D flip-flop in every cell, the output of which may be tri-stated and fed back internally within the core cell. There is also a 2-to-1 multiplexer in every cell, and an upstream AND gate in the "front end" of the cell. This AND gate is an important feature in the implementation of efficient array multipliers.

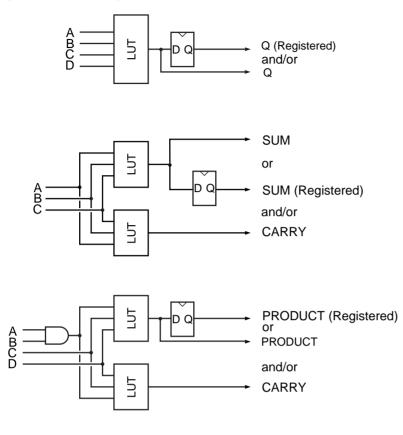


With this functionality in each core cell, the core cell can be configured in several "modes". The core cell flexibility makes the AT40KEL040 architecture well suited to most digital design application areas (see Figure 6).





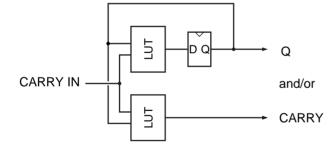
#### Figure 6. Some Single Cell Modes

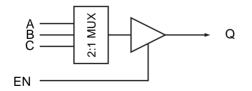


**Synthesis Mode.** This mode is particularly important for the use of VHDL design. VHDL Synthesis tools generally will produce as their output large amounts of random logic functions. Having a 4-input LUT structure gives efficient random logic optimization without the delays associated with larger LUT structures. The output of any cell may be registered, tri-stated and/or fed back into a core cell.

Arithmetic Mode is frequently used in many designs. As can be seen in the figure, the AT40KEL040 core cell can implement a 1-bit full adder (2-input adder with both Carry In and Carry Out) in one core cell. Note that the sum output in this diagram is registered. This output could then be tri-stated and/or fed back into the cell.

**DSP/Multiplier Mode.** This mode is used to efficiently implement array multipliers. An array multiplier is an array of bitwise multipliers, each implemented as a full adder with an upstream AND gate. Using this AND gate and the diagonal interconnects between cells, the array multiplier structure fits very well into the AT40K architecture.





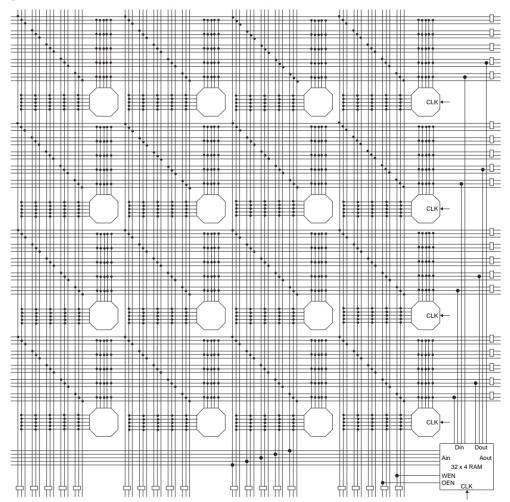
**Counter Mode.** Counters are fundamental to almost all digital designs. They are the basis of state machines, timing chains and clock dividers. A counter is essentially an increment by one function (i.e., an adder), with the input being an output (or a decode of an output) from the previous stage. A 1-bit counter can be implemented in one core cell. Again, the output can be registered, tri-stated and/or fed back.

**Tri-state/Mux Mode.** This mode is used in many telecommunications applications, where data needs to be routed through more than one possible path. The output of the core cell is very often tri-statable for many inputs to many outputs data switching.

## RAM

32 x 4 dual-ported RAM blocks are dispersed throughout the array as shown in Figure 7. A 4-bit Input Data Bus connects to four horizontal local buses distributed over four sector rows (plane 1). A 4-bit Output Data Bus connects to four horizontal local buses distributed over four sector rows (plane 2). A 5-bit Input Address Bus connects to five vertical express buses in same column. A 5-bit Output Address Bus connects to five vertical express buses in same column. Ain (input address) and Aout (output address) alternate positions in horizontally aligned RAM blocks. For the left-most RAM blocks, Aout is on the left and Ain is on the right. For the right-most RAM blocks, Ain is on the left and Aout is tied off, thus it can only be configured as a single port. For single-ported RAM, Ain is the READ/WRITE address port and Din is the (bi-directional) data port. Right-most RAM blocks can be used only for single-ported memories. WEN and OEN connect to the vertical express buses in the same column.

Figure 7. RAM Connections (One Ram Block)



Reading and writing of the 11 - 13 ns 32 x 4 dual-port FreeRAM are independent of each other. Reading the 32 x 4 dual-port RAM is completely asynchronous. Latches are transparent; when Load is logic 1, data flows through; when Load is logic 0, data is latched. These latches are used to synchronize Write Adress, Write Enable Not, and Din signals for a synchronous RAM. Each bit in the 32 x 4 dual-port RAM is also a transparent latch. The front-end latch and the memory latch together form an edge<u>-triggered flip</u> flop. When a nibble (bit = 7) is (Write) addressed and LOAD is logic 1 and WE is logic 0,





data flows through the bit. When a nibble is not (Write) addressed or LOAD is logic 0 or WE is logic 1, data is latched in the nibble. The two CLOCK muxes are controlled together; they both select CLOCK (for a synchronous RAM) or they both select "1" (for an asynchronous RAM). CLOCK is obtained from the clock for the sector-column immediately to the left and immediately above the RAM block. Writing any value to the RAM clear byte during configuration clears the RAM (see the "AT40K/40KAL Configuration Series" application note at www.atmel.com).

#### Figure 8. RAM Logic

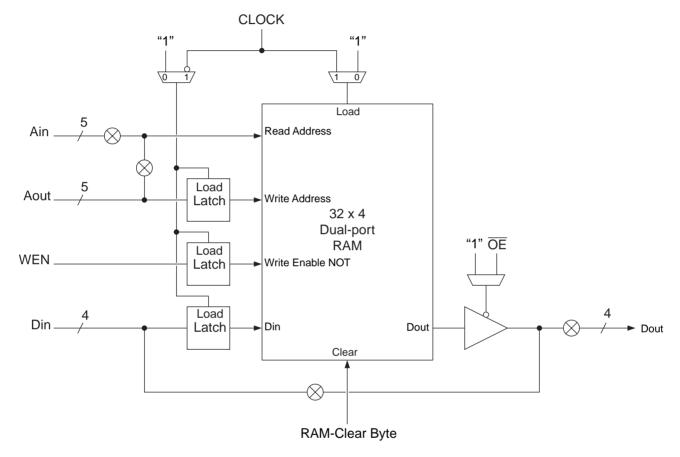
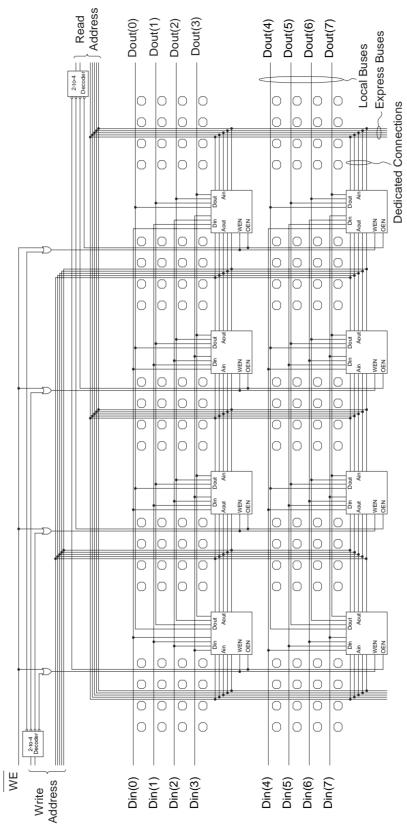


Figure 9 on page 13 shows an example of a RAM macro constructed using AT40KEL040's FreeRAM cells. The macro shown is a 128 x 8 dual-ported asynchronous RAM. Note the very small amount of external logic required to complete the address decoding for the macro. Most of the logic cells (core cells) in the sectors occupied by the RAM will be unused: they can be used for other logic in the design. This logic can be automatically generated using the macro generators.

Figure 9. RAM Example: 128 x 8 Dual-ported RAM (Asynchronous)







## **Clocking Scheme**

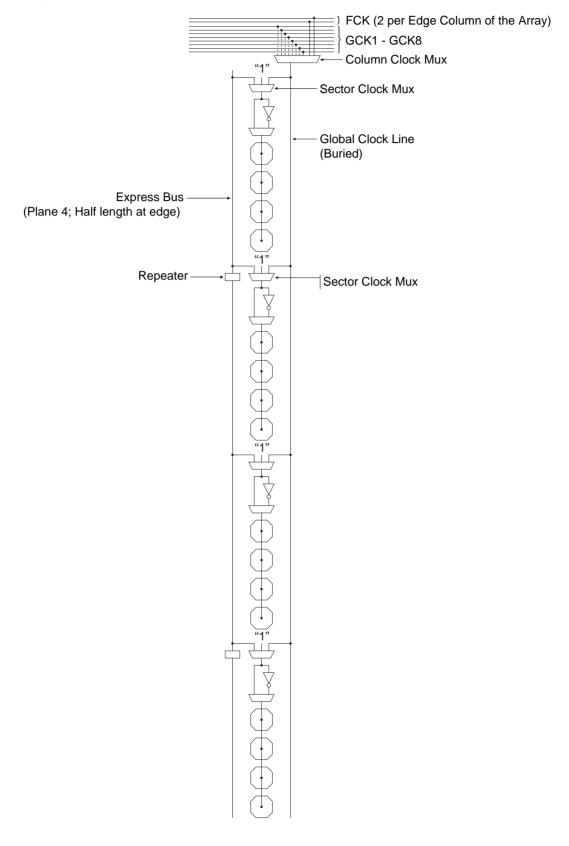
There are eight Global Clock buses (GCK1 - GCK8) on the AT40KEL040 FPGA. Each of the eight dedicated Global Clock buses is connected to one of the dual-use Global Clock pins. Any clocks used in the design should use global clocks where possible: this can be done by using Assign Pin Locks to lock the clocks to the Global Clock locations. In addition to the eight Global Clocks, there are four Fast Clocks (FCK1 - FCK4), two per edge column of the array for PCI specification. Even the derived clocks can be routed through the Global network. Access points are provided in the corners of the array to route the derived clocks into the global clock network. The IDS software tools handle derived clocks to global clock connections automatically if used.

Each column of an array has a "Column Clock mux" and a "Sector Clock mux". The Column Clock mux is at the top of every column of an array and the Sector Clock mux is at every four cells. The Column Clock mux is selected from one of the eight Global Clock buses. The clock provided to each sector column of four cells is inverted, non-inverted or tied off to "0", using the Sector Clock mux to minimize the power consumption in a sector that has no clocks. The clock can either come from the Column Clock or from the Plane 4 express bus (see Figure 10 on page 15). The extreme-left Column Clock mux has two additional inputs, FCK1 and FCK2, to provide fast clocking to left-side I/Os. The extreme-right Column Clock mux has two additional inputs as well, FCK3 and FCK4, to provide fast clocking to right-side I/Os.

The register in each cell is triggered on a rising clock edge by default. Before configuration on power-up, constant "0" is provided to each register's clock pins. After configuration on power-up, the registers either set or reset, depending on the user's choice.

The clocking scheme is designed to allow efficient use of multiple clocks with low clock skew, both within a column and across the core cell array.

Figure 10. Clocking (for One Column of Cells)





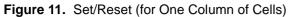


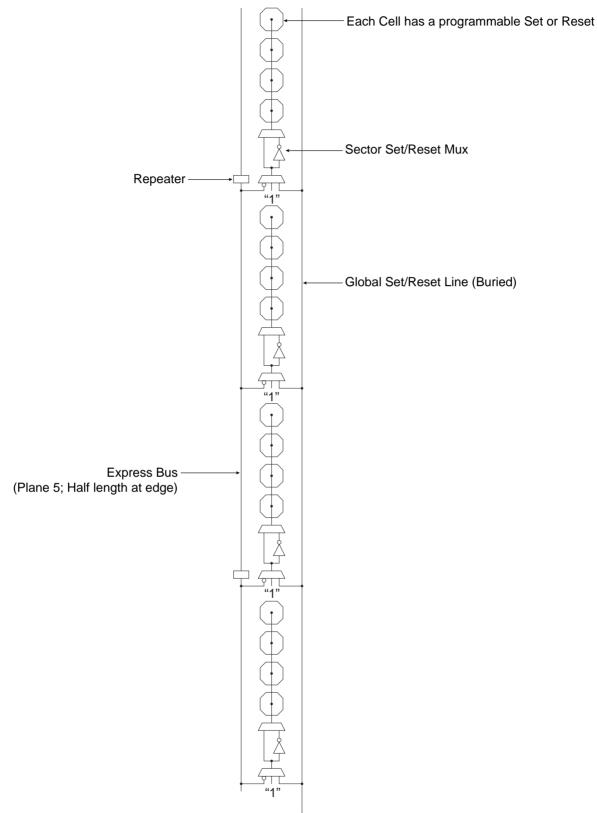
### **Set/Reset Scheme**

The AT40KEL040 family reset scheme is essentially the same as the clock scheme except that there is only one Global Reset. A dedicated Global Set/Reset bus can be driven by any User I/O, except those used for clocking (Global Clocks or Fast Clocks). The automatic placement tool will choose the reset net with the most connections to use the global resources. You can change this by using an RSBUF component in your design to indicate the global reset. Additional resets will use the express bus network.

The Global Set/Reset is distributed to each column of the array. Like Sector Clock mux, there is Sector Set/Reset mux at every four cells. Each sector column of four cells is set/reset by a Plane 5 express bus or Global Set/Reset using the Sector Set/Reset mux (Figure 11 on page 17). The set/reset provided to each sector column of four cells is either inverted or non-inverted using the Sector Reset mux.

The function of the Set/Reset input of a register is determined by a configuration bit in each cell. The Set/Reset input of a register is active low (logic 0) by default. Setting or Resetting of a register is asynchronous. Before configuration on power-up, a logic 1 (a high) is provided by each register (i.e., all registers are set at power-up).





Any User I/O can drive Global Set/Reset line



	EL
	R

I/O Structure	AT40K has registered I/Os and group enable every sector for tri-states on obuf's.
Pad	The I/O pad is the one that connects the I/O to the outside world. Note that not all I/Os have pads: the ones without pads are called Unbonded I/Os. The number of unbonded I/Os varies with the device size and package. These unbonded I/Os are used to perform a variety of bus turns at the edge of the array.
Pull-up/Pull-down	Each pad has a programmable pull-up and pull-down attached to it. This supplies a weak "1" or "0" level to the pad pin. When all other drivers are off, this control will dictate the signal level of the pad pin. The input stage of each I/O cell has a number of parameters that can be programmed either as properties in schematic entry or in the I/O Pad Attributes editor in IDS.
CMOS	The threshold level is a CMOS-compatible level.
Schmitt	A Schmitt trigger circuit can be enabled on the inputs. The Schmitt trigger is a regenera- tive comparator circuit that adds 1V hysteresis to the input. This effectively improves the rise and fall times (leading and trailing edges) of the incoming signal and can be useful for filtering out noise.
Delays	The input buffer can be programmed to include four different intrinsic delays as specified in the AC timing characteristics. This feature is useful for meeting data hold require- ments for the input signal.
Drive	The output drive capabilities of each I/O are programmable. They can be set to FAST, MEDIUM or SLOW (using IDS tool). The FAST setting has the highest drive capability (16 mA at 5V) buffer and the fastest slew rate. MEDIUM produces a medium drive (12 mA at 5V) buffer, while SLOW yields a standard (4 mA at 5V) buffer.
Tri-State	The output of each I/O can be made tri-state (0, 1 or Z), open source (1 or Z) or open drain (0 or Z) by programming an I/O's Source Selection mux. Of course, the output can be normal (0 or 1), as well.
Source Selection Mux	The Source Selection mux selects the source for the output signal of an I/O. See Figure 12 on page 21.
Primary, Secondary and Corner I/Os	The AT40KEL040 has three kinds of I/Os: Primary I/O, Secondary I/O and a Corner I/O. Every edge cell except corner cells on the AT40KEL040 has access to one Primary I/O and two Secondary I/Os.
Primary I/O	Every logic cell at the edge of the FPGA array has a direct orthogonal connection to and from a Primary I/O cell. The Primary I/O interfaces directly to its adjacent core cell. It also connects into the repeaters on the row immediately above and below the adjacent core cell. In addition, each Primary I/O also connects into the busing network of the three nearest edge cells. This is an extremely powerful feature, as it provides logic cells toward the center of the array with fast access to I/Os via local and express buses. It can be seen from the diagram that a given Primary I/O can be accessed from any logic cell on three separate rows or columns of the FPGA. See Figures 12a and 13a.
Secondary I/O	Every logic cell at the edge of the FPGA array has two direct diagonal connections to a Secondary I/O cell. The Secondary I/O is located between core cell locations. This I/O

connects on the diagonal inputs to the cell above and the cell below. It also connects to the repeater of the cell above and below. In addition, each Secondary I/O also connects into the busing network of the two nearest edge cells. This is an extremely powerful feature, as it provides logic cells toward the center of the array with fast access to I/Os via local and express buses. It can be seen from the diagram that a given Secondary I/O can be accessed from any logic cell on two rows or columns of the FPGA. See Figure 12a and Figure 13b.

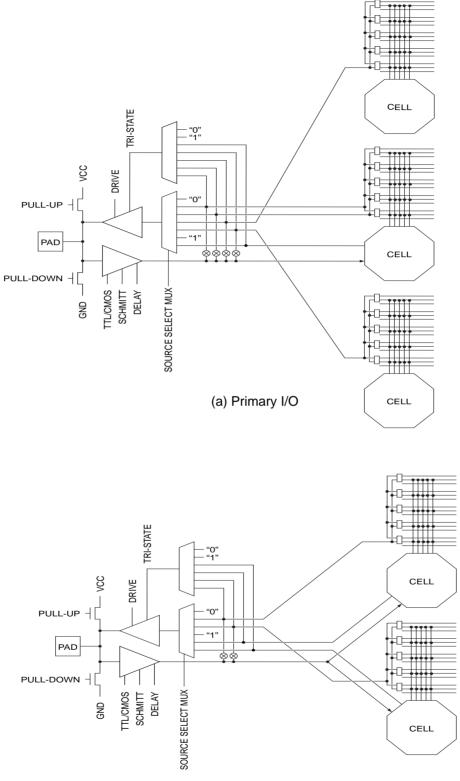
#### Corner I/O

Logic cells at the corner of the FPGA array have direct-connect access to five separate I/Os: 2 Primary, 2 Secondary and 1 Corner I/O. Corner I/Os are like an extra Secondary I/O at each corner of the array. With the inclusion of Corner I/Os, an AT40KEL040 FPGA with n x n core cells always has 8n I/Os. As the diagram shows, Corner I/Os can be accessed both from the corner logic cell and the horizontal and vertical busing networks running along the edges of the array. This means that many different edge logic cells can access the Corner I/Os. See Figure 14.



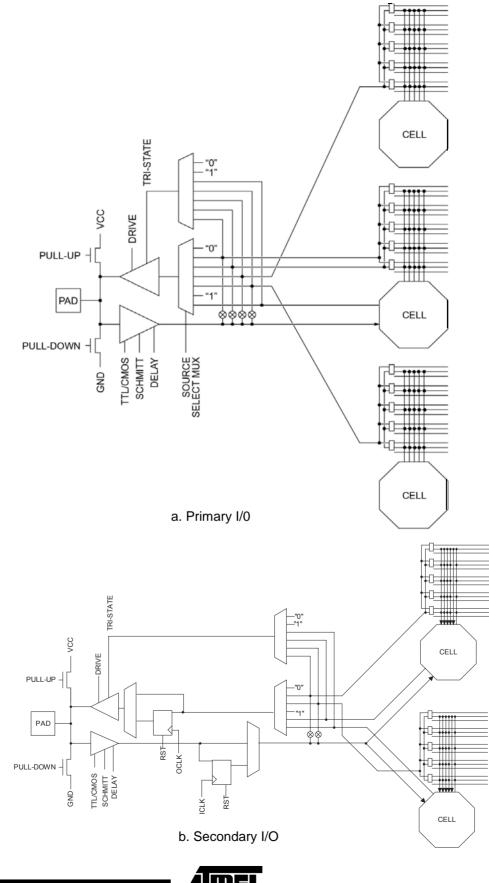


Figure 12. South I/O (Mirrored for North I/O)



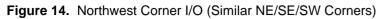
(b) Secondary I/O

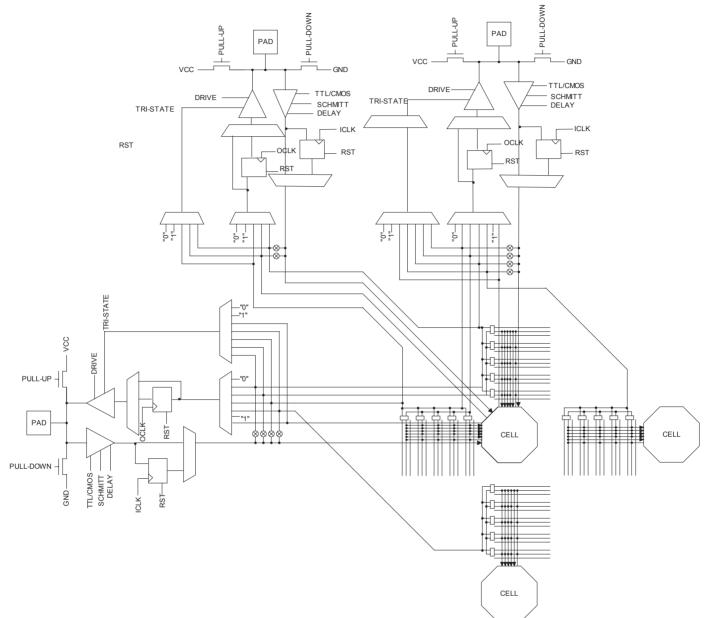
Figure 13. West I/O (Mirrored for East I/O)



4







## **Electrical Characteristics**

### **Absolute Maximum Ratings\***

Operating Temperature55°C to +125°C
Storage Temperature65 °C to +150°C
Junction Temperature+150°C
Voltage on Any Pin with Respect to Ground $^{(1)}$ 0.5V to $\rm V_{\rm CC}$ +0.5V
Supply Voltage (V <sub>CC</sub> )
ESD (R <sub>ZAP</sub> = 1.5K, C <sub>ZAP</sub> = 100 pF)

\*Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those listed under operating conditions is not implied. Exposure to Absolute Maximum Rating conditions for extended periods of time may affect device reliability.

1. For DC Input Voltage (V<sub>1</sub>) Minimum voltage of -0.5V DC, which may undershoot to -2.0V for pulses of less than 20 ns.

### **DC and AC Operating Range**

Operating Temperature	-55°C to +125°C	
V <sub>CC</sub> Power Supply	$3.3V \pm 0.3V$	
	High (V <sub>IHC</sub> )	70% - 100% V <sub>CC</sub>
Input Voltage Level (CMOS)	Low (V <sub>ILC</sub> )	0 - 30% V <sub>CC</sub>





### **DC Characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Units
. /		CMOS	70% V <sub>CC</sub>			V
V <sub>IH</sub>	High-level Input Voltage	TTL	2.0			V
\ <i>/</i>		CMOS	-0.3		30% V <sub>CC</sub>	V
V <sub>IL</sub>	Low-level Input Voltage	TTL	-0.3		0.8	V
		$I_{OH} = -4 \text{ mA}$ $V_{CC} = 3.0 \text{V}$	2.4			V
V <sub>OH</sub>	High-level Output Voltage	I <sub>OH</sub> = -12 mA V <sub>CC</sub> = 3.0V	2.4			V
		I <sub>OH</sub> = -16 mA V <sub>CC</sub> = 3.0V	2.4			V
		I <sub>OL</sub> = +4 mA V <sub>CC</sub> = 3.0V			0.4	V
V <sub>OL</sub>	Low-level Output Voltage	I <sub>OL</sub> = +12 mA V <sub>CC</sub> = 3.0V			0.4	V
		I <sub>OL</sub> = +16 mA V <sub>CC</sub> = 3.0V			0.4	V
		V <sub>IN</sub> = V <sub>CC</sub> max	-5		5	μA
IIH	High-level Input Current	With pull-down, $V_{IN} = V_{CC}$	20	75	300	μA
		$V_{IN} = V_{SS}$	-5		5	μA
IIL	Low-level Input Current	With pull-up, $V_{IN} = V_{SS}$	-300.0	-50	-20	μA
	High-level Tri-state Output	Without pull-down, $V_{OUT} = V_{CC} max$	-5		5	μA
I <sub>OZH</sub>	Leakage Current	With pull-down, $V_{OUT} = V_{CC}$ max	20		300	μA
		Without pull-up, $V_{OUT} = V_{SS}$	-5			mA
OZL	Low-level Tri-state Output Leakage Current	With pull-up, $V_{OUT} = V_{SS}$ for CON	-500	-150.0	-110	μA
cc	Standby Current Consumption	Standby, unprogrammed		1	5	mA
C <sub>IN</sub>	Input Capacitance	All pins			10	pF

Note: 1. Parameter based on characterization and simulation; it is not tested in production.

# Power-On Power Supply Requirements

**ply** Atmel FPGAs require a minimum rated power supply current capacity to ensure proper initialization, and the power supply ramp-up time does not affect the current required. A fast ramp-up time requires more current than a slow ramp-up time.

#### Table 3. Power-on Supply Requirements

Description	Maximum Current <sup>(1)(2)</sup>
Maximum Current Supply	1.2 A

Note: 1. Devices are guaranteed to initialize properly at 50% of the minimum current listed above. A larger capacity power supply may result in a larger initiallization current.

2. Ramp-up time is measured from 0V DC to 3.6V DC. Peak current required lasts less than 2 ms, and occurs near the internal power on reset threshold voltage.

### AC Timing Characteristics

Delays are based on fixed loads and are described in the notes. Maximum times based on worst case:  $V_{cc} = 3.0V$ , temperature = 125°C. Minimum times based on best case:  $V_{cc} = 3.60V$ , temperature = -55°C. Maximum delays are the average of t<sub>PDLH</sub> and t<sub>PDHL</sub>.

Cell Function	Parameter	Path	Value	Units	Notes
Core				4	
2-input gate	t <sub>PD</sub> (max)	x/y -> x/y	2.9	ns	1 unit load
3-input gate	t <sub>PD</sub> (max)	x/y/z -> x/y	3.1	ns	1 unit load
3-input gate	t <sub>PD</sub> (max)	x/y/w -> x/y	3.5	ns	1 unit load
4-input gate	t <sub>PD</sub> (max)	x/y/w/z -> x/y	3.5	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	y -> y	2.8	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	x -> y	2.6	ns	1 unit load
Fast crry	t <sub>PD</sub> (max)	y -> x	2.8	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	x -> x	2.9	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	w -> y	3.5	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	W -> X	3.5	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	z -> y	3.1	ns	1 unit load
Fast carry	t <sub>PD</sub> (max)	Z -> X	3.0	ns	1 unit load
DFF	t <sub>PD</sub> (max)	Clk -> x/y	4.3	ns	1 unit load
DFF	t <sub>PD</sub> (max)	R -> x/y	4.1	ns	1 unit load
DFF	t <sub>PD</sub> (max)	S -> x/y	2.8	ns	1 unit load
DFF	t <sub>PD</sub> (max)	q -> w	4.3	ns	
Incremental -> L	t <sub>PD</sub> (max)	x/y -> L	2.5	ns	1 unit load
Local output enable	t <sub>PZX</sub> (max)	oe -> L	2.9	ns	1 unit load
Local output enable	t <sub>PXZ</sub> (max)	oe -> L	0.9	ns	

### AC Timing Characteristics

All input I/O characteristics measured from V<sub>IH</sub> of 50% of V<sub>DD</sub> at the pad (CMOS threshold) to the internal V<sub>IH</sub> of 50% of V<sub>DD</sub>. All output I/O characteristics are measured as the average of  $t_{PDLH}$  and  $t_{PDHL}$  to the pad V<sub>IH</sub> of 50% of V<sub>DD</sub>.

Cell Function	Parameter	Path	Value	Units	Notes
Repeaters					
Repeater	t <sub>PD</sub> (max)	L -> E	1.3	ns	1 unit load
Repeater	t <sub>PD</sub> (max)	E -> E	1.3	ns	1 unit load
Repeater	t <sub>PD</sub> (max)	L -> L	1.3	ns	1 unit load
Repeater	t <sub>PD</sub> (max)	E -> L	1.3	ns	1 unit load
Repeater	t <sub>PD</sub> (max)	E -> 10	0.7	ns	1 unit load
Repeater	t <sub>PD</sub> (max)	L -> 10	0.7	ns	1 unit load





Cell Function	Parameter	Path	Value	Units	Notes
I/O					
Input	t <sub>PD</sub> (max)	pad -> x/y	5.4	ns	no extra delay
Input	t <sub>PD</sub> (max)	pad -> x/y	7.6	ns	1 extra delay
Input	t <sub>PD</sub> (max)	pad -> x/y	11.4	ns	2 extra delays
Input	t <sub>PD</sub> (max)	pad -> x/y	14.9	ns	3 extra delays
Output, slow	t <sub>PD</sub> (max)	x/y/E/L -> pad	16.0	ns	50 pf load
Output, medium	t <sub>PD</sub> (max)	x/y/E/L -> pad	14.8	ns	50 pf load
Output, fast	t <sub>PD</sub> (max)	x/y/E/L -> pad	11.2	ns	50 pf load
Output, slow	t <sub>PZX</sub> (max)	oe -> pad	16.4	ns	50 pf load
Output, slow	t <sub>PXZ</sub> (max)	oe -> pad	5.1	ns	50 pf load
Output, medium	t <sub>PZX</sub> (max)	oe -> pad	14.1	ns	50 pf load
Output, medium	t <sub>PXZ</sub> (max)	oe -> pad	9.1	ns	50 pf load
Output, fast	t <sub>PZX</sub> (max)	oe -> pad	11.4	ns	50 pf load
Output, fast	t <sub>PXZ</sub> (max)	oe -> pad	9.5	ns	50 pf load

### AC Timing Characteristics

Clocks and Reset Input buffers are measured from a  $V_{IH}$  of 1.5V at the input pad to the internal  $V_{IH}$  of 50% of  $V_{CC}$ . Maximum times for clock input buffers and internal drivers are measured for rising edge delays only.

Cell Function	Parameter	Path	Value	Units	Notes
Global Clocks and Set/Re	set				
GCK Input buffer	t <sub>PD</sub> (max)	pad -> clock	3.3	ns	rising edge clock
FCK Input buffer	t <sub>PD</sub> (max)	pad -> clock	1.9	ns	rising edge clock
Clock column driver	t <sub>PD</sub> (max)	clock -> colclk	1.7	ns	rising edge clock
Clock sector driver	t <sub>PD</sub> (max)	colclk -> secclk	0.8	ns	rising edge clock
GSRN Input buffer	t <sub>PD</sub> (max)	colclk -> secclk	10.3	ns	
Global clock to output	t <sub>PD</sub> (max)	clock pad -> out	21.3	ns	rising edge clock fully loaded clock tree rising edge DFF 20 mA output buffer 50 pf pin load
Fast clock to output	t <sub>PD</sub> (max)	clock pad -> out	19.9	ns	rising edge clock fully loaded clock tree rising edge DFF 20 mA output buffer 50 pf pin load

Notes: 1. CMOS buffer delays are measured from a  $V_{IH}$  of 1/2  $V_{CC}$  at the pad to the internal  $V_{IH}$  at A. The input buffer load is constant.

2. Buffer delay is to a pad voltage of 1.5V with one output switching.

3. Parameter based on characterization and simulation; not tested in production.

4. Exact power calculation is available in Atmel FPGA Designer software.



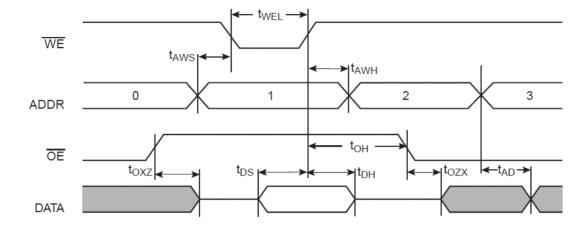


## AC Timing Characteristics

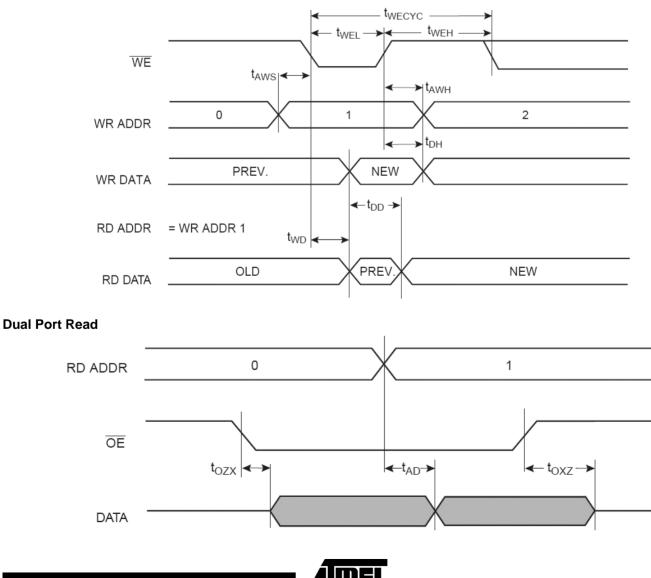
Cell Function	Parameter	Path	Value	Units	Notes
Async RAM					
Write	t <sub>wecyc</sub> (min)	cycle time	28	ns	
Write	t <sub>WEL</sub> (min)	we	6.5	ns	pulse width low
Write	t <sub>wEH</sub> (min)	we	6.5	ns	pulse width high
Write	t <sub>setup</sub> (min)	wr addr setup -> we	7.0	ns	
Write	t <sub>hold</sub> (min)	wr addr hold -> we	0.0	ns	
Write	t <sub>setup</sub> (min)	din setup -> we	6.5	ns	
Write	t <sub>hold</sub> (min)	din hold -> we	0.0	ns	
Write	t <sub>hold</sub> (min)	oe hold -> we	0.0	ns	
Write/Read	t <sub>PD</sub> (max)	din -> dout	14.1	ns	rd addr = wr addr
Read	t <sub>PD</sub> (max)	rd addr -> dout	13.1	ns	
Read	t <sub>PZX</sub> (max)	oe -> dout	4.5	ns	
Read	t <sub>PXZ</sub> (max)	oe -> dout	4.5	ns	
Sync RAM					
Write	t <sub>CYC</sub> (min)	cycle time	28	ns	
Write	t <sub>CLKL</sub> (min)	clk	6.5	ns	pulse width low
Write	t <sub>CLKH</sub> (min)	clk	6.5	ns	pulse width high
Write	t <sub>setup</sub> (min)	we setup -> clk	5.0	ns	
Write	t <sub>hold</sub> (min)	we hold -> clk	0.0	ns	
Write	t <sub>setup</sub> (min)	wr addr setup -> clk	6.5	ns	
Write	t <sub>hold</sub> (min)	wr addr hold -> clk	0.0	ns	
Write	t <sub>setup</sub> (min)	wr data setup -> clk	5.1	ns	
Write	t <sub>hold</sub> (min)	wr data hold -> clk	0.0	ns	
Write/Read	t <sub>PD</sub> (max)	din -> dout	14.1	ns	rd addr = wr addr
Write/Read	t <sub>PD</sub> (max)	clk -> dout	7.9	ns	rd addr = wr addr
Read	t <sub>PD</sub> (max)	rd addr -> dout	13.1	ns	
Read	t <sub>PZX</sub> (max)	oe -> dout	4.5	ns	
Read	t <sub>PXZ</sub> (max)	oe -> dout	4.5	ns	

### FreeRAM Asynchronous Timing Characteristics

#### Single Port Write/Read



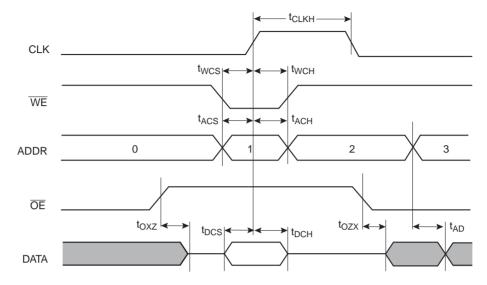
#### **Dual Port Write with Read**



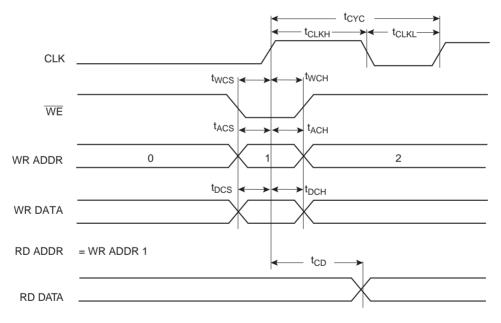


### FreeRAM Synchronous Timing Characteristics

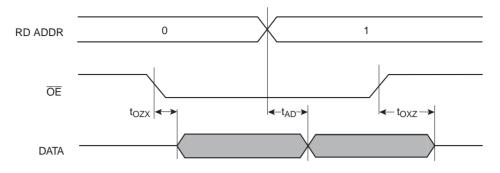
#### Single Port Write/Read



#### **Dual Port Write with Read**



## **Dual Port Read**







#### Table 4. MQFP F-160

Pin Number	Signal
1	VCC
2	I/O384_GCK8_A15
3	I/O383_A14
4	I/O382
5	I/O381
6	I/O372_A13
7	I/O371_A12
8	I/O370
9	I/O369
10	GND
11	I/O360
12	I/O359
13	I/O348_A11
14	I/O347_A10
15	I/O344
16	I/O343
17	I/O338_A9
18	I/O337_A8
19	VCC
20	GND
21	I/O336_A7
22	I/O335_A6
23	I/O330
24	I/O329
25	I/O328
26	I/O326_A5
27	I/O325_A4
28	I/O314
29	I/O313
30	GND
31	I/O304
32	I/O303
33	I/O298_A3

Pin Number	Signal
34	I/O297_CS1_A2
35	I/O292
36	I/O291
37	I/O290_GCK7_A1
38	I/O289_A0
39	GND
40	TESTCLOCK
41	VCC
42	CCLK
43	I/O288_GCK6
44	I/O287_D0
45	I/O286
46	I/O285
47	I/O278
48	I/O277_D1
49	I/O274
50	I/O273
51	GND
52	I/O262_FCK4
53	I/O261
54	I/O260
55	I/O259_D2
56	I/O246
57	I/O245
58	I/O242_CHECK
59	I/O241_D3
60	GND
61	VCC
62	I/O240
63	I/O239_D4
64	I/O236
65	I/O235
66	I/O222_CS0
67	I/O221_D5

Pin Number	Signal
68	I/O220
69	I/O219_FCK3
70	GND
71	I/O208
72	I/O207
73	I/O206
74	I/O205_D6
75	I/O196
76	I/O195
77	I/O194_GCK5
78	I/O193_D7
79	RESETN
80	VCC
81	CON
82	GND
83	I/O192_GCK4
84	I/O191_D8
85	I/O190
86	I/O189
87	I/O184_D9
88	I/O183_D10
89	I/O180
90	I/O179
91	GND
92	I/O168
93	I/O167
94	I/O166_D11
95	I/O165_D12
96	I/O152
97	I/O151
98	I/O146_D13
99	I/O145_D14
100	GND
101	VCC



Pin Number 102	Signal
102	<b>U</b>
	I/O144_INIT
103	I/O143_D15
104	I/O138
105	I/O137
106	I/O124
107	I/O123
108	I/O122
109	I/O121
110	GND
111	I/O110
112	I/O109
113	I/O102_LDC
114	I/O101
115	I/O100
116	I/O99
117	I/O98_HDC
118	I/O97_GCK3
119	M2
120	VCC
121	MO
122	GND
123	M1
124	I/O96_GCK2
125	I/O95_OTS
126	I/O94
127	I/O93
128	I/O90
129	I/O89
130	I/O84
131	I/O83
132	GND
133	I/072_FCK2
134	I/071
135	I/O70

Pin Number	Signal
136	I/O69
137	I/O54
138	I/O53
139	I/O50
140	I/O49
141	VCC
142	GND
143	I/O48_A23
144	I/O47_A22
145	I/O44
146	I/O43
147	I/O28_A21
148	I/O27_A20
149	I/O26
150	I/O25_FCK1
151	GND
152	I/O16
153	I/O15
154	I/O6_A19
155	I/O5_A18
156	I/O4
157	I/O3
158	I/O2_A17
159	I/O1_GCLK1_A16
160	GND



#### Table 5. MQFP - F256

	IQFF - F230
Pin Number	Signal
1	IO384_GCK8_A15
2	IO383_A14
3	IO382
4	IO381
5	IO378
6	IO377
7	GND
8	VCC
9	IO375
10	IO374
11	IO372_A13
12	IO371_A12
13	IO370
14	IO369
15	IO366
16	IO365
17	IO362
18	IO360
19	IO359
20	IO358
21	IO356
22	IO355
23	IO353
24	IO352
25	IO349
26	IO348_A11
27	IO347_A10
28	IO346
29	IO344
30	IO343
31	IO338_A9
32	IO337_A8
33	IO336_A7

Pin Number	Signal
34	IO335 A6
35	IO334
36	IO330
37	IO329
38	IO323
39	IO326_A5
40	IO325_A4
40	IO323_A4
42	IO323
43	IO321
44	IO320
45	IO318
46	IO317
47	IO314
48	IO313
49	IO312
50	IO311
51	IO308
52	IO307
53	IO304
54	IO303
55	IO301
56	IO298_A3
57	GND
58	VCC
59	IO297_CS1_A2
60	IO291
61	IO292
62	IO290_GCK7_A1
63	IO289_A0
64	TESTCLOCK
65	CCLK
66	IO288_GCK6
67	IO287_D0

	Signal
68	IO286
69	IO285
70	IO282
71	GND
72	VCC
73	IO278
74	IO277_D1
75	IO276
76	IO274
77	IO273
78	IO272
79	IO270
80	IO269
81	IO267
82	IO266
83	IO262_FCK4
84	IO261
85	IO260
86	IO259_D2
87	IO258
88	IO257
89	IO254
90	IO253
91	IO252
92	IO251
93	IO248
94	IO246
95	IO245
96	IO242_CHECK
97	IO241_D3
98	IO240
99	IO239_D4
100	IO236
101	IO235



	1
Pin Number	Signal
102	IO234
103	IO232
104	IO230
105	IO228
106	IO227
107	IO225
108	IO224
109	IO222_CS0
110	IO221_D5
111	IO220
112	IO219_FCK3
113	IO216
114	IO215
115	IO212
116	IO208
117	IO207
118	IO206
119	IO205_D6
120	IO204
121	GND
122	VCC
123	IO203
124	IO196
125	IO195
126	IO194_GCK5
127	IO193_D7
128	RESETN
129	CON
130	IO192_GCK4
131	IO191_D8
132	IO190
133	IO189
134	IO186
135	GND

Pin Number	Signal
136	VCC
137	IO184_D9
138	IO183_D10
139	IO181
140	IO180
141	IO179
142	IO177
143	IO174
144	IO173
145	IO171
146	IO168
147	IO167
148	IO166_D11
149	IO165_D12
150	IO163
151	IO162
152	IO161
153	IO158
154	IO157
155	IO156
156	IO152
157	IO151
158	IO150
159	IO149
160	IO146_D13
161	IO145_D14
162	IO144_INIT
163	IO143_D15
164	IO141
138	IO183_D10
139	IO181
140	IO180
141	IO179
142	IO177

Pin			
Number	Signal		
143	IO174		
144	IO173		
145	IO171		
146	IO168		
147	IO167		
148	IO166_D11		
149	IO165_D12		
150	IO163		
151	IO162		
152	IO161		
153	IO158		
154	IO157		
155	IO156		
156	IO152		
157	IO151		
158	IO150		
159	IO149		
160	IO146_D13		
161	IO145_D14		
162	IO144_INIT		
163	IO143_D15		
164	IO141		
165	IO138		
166	IO137		
167	IO136		
168	IO134		
169	IO132		
170	IO131		
171	IO129		
172	IO128		
173	IO124		
174	IO123		
175	IO122		
176	IO121		



Pin Number	Signal		
177	IO120		
178	IO119		
179	IO116		
180	IO115		
181	IO113		
182	IO110		
183	IO109		
184	IO101		
185	GND		
186	VCC		
187	IO102_LDC		
188	IO99		
189	IO100		
190	IO98_HDC		
191	IO97_GCK3		
192	M2		
193	MO		
194	M1		
195	IO96_GCK2		
196	IO95_OTS		
197	IO94		
198	IO93		
199	GND		
200	VCC		
201	IO90		
202	IO89		
203	IO86		
204	IO85		
205	IO84		
206	IO83		
207	IO80		
208	IO79		
209	IO77		
210	IO76		

Pin Number	Signal	
211	-	
	IO72_FCK2	
212	IO71	
213	IO70	
214	IO69	
215	IO67	
216	IO66	
217	IO63	
218	IO62	
219	IO60	
220	IO59	
221	IO57	
222	IO56	
223	IO54	
224	IO53	
225	IO50	
226	IO49	
227	IO48_A23	
228	IO47_A22	
229	IO44	
230	IO43	
231	IO41	
232	IO39	
233	IO36	
234	IO35	
235	IO34	
236	IO33	
237	IO30	
238	IO29	
239	IO28_A21	
240	IO27_A20	
241	IO27_720	
242	IO25_FCK1	
243	IO21	
244	1021	
277 277	1020	

Pin Number	Signal		
245	IO18		
246	IO16		
247	IO15		
248	IO13		
249	GND		
250	VCC		
251	IO6_A19		
252	IO5_A18		
253	104		
254	IO3		
255	IO2_A17		
256	IO1_GCLK1_A16		

## Part/Package Availability and User I/O Counts (Including Dual-function Pins)

Package	AT40KEL040	
MQFPF 160	130	
MQFPF 256 <sup>(1)</sup>	240	

Note: 1. Contact Atmel for availability.





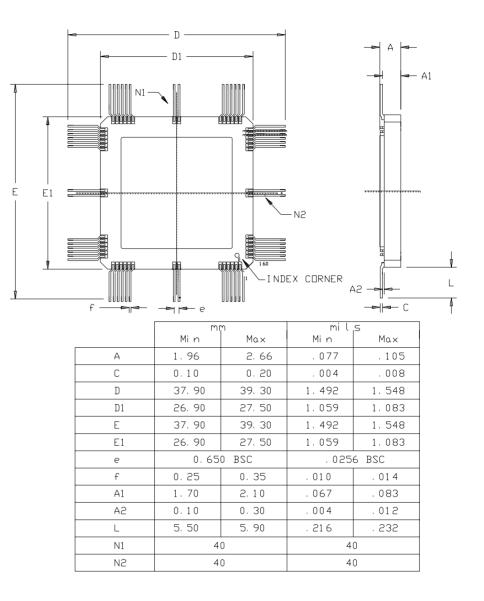
## **Ordering Information**

Part Number	Package	Temperature Range	Quality Flow
AT40KEL040KW1-E	MQFPF160	25°C	Engineering Samples
5962-0325001QXC	MQFPF160	-55° to +125°C	QML Q
5962-0325001VXC	MQFPF160	-55° to +125°C	QML V
AT40KEL040KW1SB	MQFPF160	-55° to +125°C	SCC B
AT40KEL040KZ1-E <sup>(1)</sup>	MQFPF256	25°C	Engineering Samples
5962-0325001QYC <sup>(1)</sup>	MQFPF256	-55° to +125°C	QML Q
5962-0325001VYC <sup>(1)</sup>	MQFPF256	-55° to +125°C	QML V
AT40KEL040KZ1SB <sup>(1)</sup>	MQFPF256	-55° to +125°C	SCC B

Notes: 1. Contact Atmel for availability

## Package Drawing

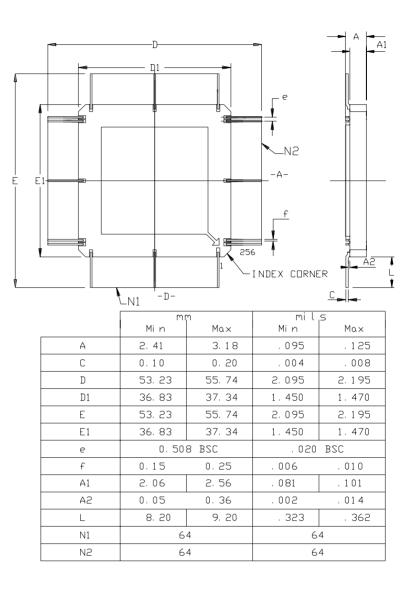
## Multilayer Quad Flat Pack (MQFP) 160-pin







## Multilayer Quad Flat Pack (MQFP) 256-pin



## **Datasheet Change Log**

Changes from 4155B - 06/03 to 4155C 04/04

- 1. Addition of MQFP F256 package information
- 2. Pad/ Pin assignment updated. Table 4 on page 31.
- 3. Ordering information updated
- 4. Reference to design tools

Changes from 4155C - 06/03 to 4155D 04/04

1. Update of radiation hardness performance, page 1.

Changes from 4155D 04/04 - to 4155E 06/04

1. Updated FreeRAM timing characteristics, Section "FreeRAM Asynchronous Timing Characteristics", page 29.





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